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Joseph Mancuso

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner:

In re patent application of:

Applicants: Rodney E. Schwartz et al.

Serial No: 08/072,206 Art Unit: 2616

Filing Date: June 4, 1993

Title: INTEGRATED CIRCUIT PROBE CARD INSPECTION SYSTEM

Assistant Commissioner for Patents Washington, D.C. 20231

**RESPONSE TO OFFICE ACTION DATED JULY 8, 1996** 

Dear Sir:

Favorable reconsideration of the above-identified application is respectfully requested in view of the following amendments and comments.

A petition and fee for a two-month extension of time to respond to the Office Action is being filed concurrently herewith.

## **AMENDMENTS**

## In the Claims:

Please amend claim 8 as follows:

(Twice Amended) An apparatus for determining the length of a probe tip included on a spring contact probe having a shank from which said probe tip extends, comprising:

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